# MSKSEMI 美森科







TVS



TSS



MOV



GDT



PIFF

**FDS4435A-MS** 

**Product specification** 





#### **Features**

- $-30V,-9A, RDS(ON) = 16m\Omega@VGS = -10V$
- Fast switching
- Green Device Available
- Suit for -4.5V Gate Drive Applications

## **Application**

- MB / VGA / Vcore
- POL Applications
- Load Switch
- LED Application

BVDSS	RDSON	ID
-30V	16mΩ	-9A

#### **Reference News**

PACKAGE OUTLINE	Pin Configuration	Marking
SOP-8	G	MSKSEMI FDS4435A MS30

## **Absolute Maximum Ratings** (TA=25℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
Vos	Drain-Source Voltage	-30	V
Vgs	Gate-Source Voltage	±20	V
le .	Drain Current - Continuous (T <sub>C</sub> =25°C)	-9	Α
ID	Drain Current - Continuous (T <sub>C</sub> =75°C)	-5.1	Α
I <sub>DM</sub>	Drain Current - Pulsed¹	-27	Α
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> =25°C)	2.1	W
FU	Power Dissipation - Derate above 25°C	0.017	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 125	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		60	°C/W



## Electrical Characteristics (TJ=25 ℃, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.03		V/°C
	Drain Source Leekage Current	V <sub>DS</sub> =-30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			-1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			-10	uA
Igss	Gate-Source Leakage Current	$V_{GS}$ = $\pm 20V$ , $V_{DS}$ = $0V$			±100	nA

#### **On Characteristics**

D	Static Drain-Source On-Resistance	V <sub>GS</sub> =-10V , I <sub>D</sub> =-8A		16	22	mΩ
R <sub>DS(ON)</sub>   Static Drain-Source On-Resistance		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-5A		22	32	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage		-1.0	-1.6	-2.5	V
△V <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=-250uA$		4		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-3A		6.8		S

**Dynamic and switching Characteristics** 

	<u> </u>				
Qg	Total Gate Charge <sup>2,3</sup>			11	
Q <sub>gs</sub>	Gate-Source Charge <sup>2,3</sup>	V <sub>DS</sub> =-15V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-5A		3.4	 nC
Q <sub>gd</sub>	Gate-Drain Charge <sup>2, 3</sup>			4.2	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2,3</sup>			5.8	
Tr	Rise Time <sup>2, 3</sup> $V_{DD}$ =-15V , $V_{GS}$ =-10V , $R_G$ =6 $\Omega$			18.8	
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2, 3</sup>	l <sub>D</sub> =-1A		46.9	 ns
T <sub>f</sub>	Fall Time <sup>2, 3</sup>			12.3	
Ciss	Input Capacitance			1250	
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , F=1MHz		160	 pF
C <sub>rss</sub>	Reverse Transfer Capacitance			90	

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V =V =0V Force Current			-9	Α
Ism	Pulsed Source Current	-V <sub>G</sub> =V <sub>D</sub> =0V,Force Current			-16	Α
Vsp	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1.3	V

#### Note:

- Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%. Essentially independent of operating temperature. 2.
- 3.

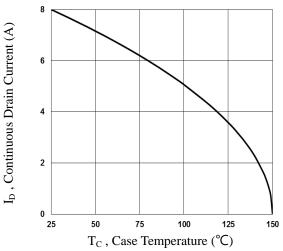


Fig.1 Continuous Drain Current vs. T<sub>c</sub>

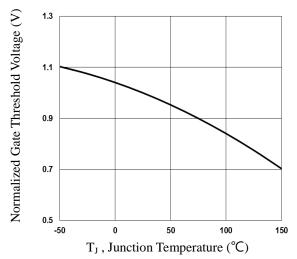


Fig.3 Normalized  $V_{th}$  vs.  $T_J$ 

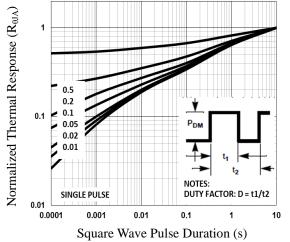


Fig.5 Normalized Transient Impedance

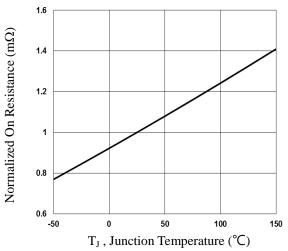


Fig.2 Normalized RDSON vs. T,

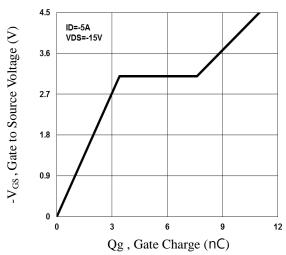


Fig.4 Gate Charge Waveform

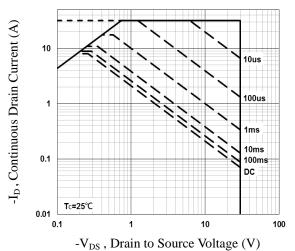
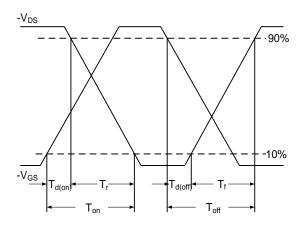


Fig.6 Maximum Safe Operation Area





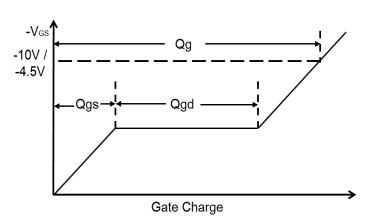
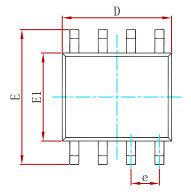
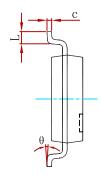


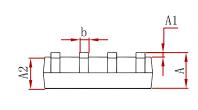
Fig.8 Gate Charge Waveform



#### **PACKAGE MECHANICAL DATA**

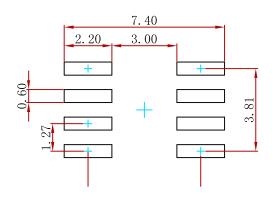






Symbol	Dimensions In	n Millimeters	Dimension	s In Inches
3y 111001	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
С	0.170	0. 250	0.007	0.010
D	4.800	5. 000	0.189	0. 197
e	1. 270 (BSC)		0.050	(BSC)
Е	5. 800	6. 200	0. 228	0. 244
E1	3.800	4.000	0.150	0. 157
L	0.400	1. 270	0.016	0.050
θ	0°	8°	0°	8°

### **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.
  2.General tolerance:± 0.05mm.
  3.The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
FDS4435A-MS	SOP-8	3000



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